

COPY

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. SEA/3369		Serial No.		
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)				Applicant Shih-Fu Lee		Confirmation No.:		
Examiner JUN 06 2005				Filing Date		Group		
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
✓	LDW	A1	6,618,215 B2	09-09-2003	Fung, et al.	360	31	03-06-2002
✓		A2	6,615,387 B1	09-02-2003	Williamson, et al.	714	785	09-02-2003
✓		A3	6,611,397 B1	08-26-2003	Nguyen, H.V.	360	77.08	06-04-1999
✓		A4	6,606,211 B1	08-12-2003	Lim, et al.	360	53	04-19-2000
✓		A5	6,603,636 B2	08-05-2003	Schwandt, et al.	360	99.12	06-29-2001
✓		A6	6,590,388 B2	07-08-2003	Arnaout, et al.	324	210	06-26-2001
✓		A7	6,587,293 B1	07-01-2003	Ding, et al.	360	51	02-29-2000
✓		A8	6,574,068 B1	06-03-2003	Hampshire, et al.	360	77.08	04-18-2000
✓		A9	6,483,299 B1	11-19-2002	Pressesky, et al.	324	212	11-09-2000
✓		A10	6,476,995 B1	11-05-2002	Liu, et al.	360	75	01-14-2000
✓		A11	6,405,449 B1	06-18-2002	Sundaram, et al.	33	645	02-07-2001
✓		A12	6,404,590 B1	06-11-2002	Kuo, et al.	360	135	03-18-1998
✓		A13	6,396,773 B1	05-28-2002	Kuo, D.S.	369	13.02	12-11-1998
✓		A14	6,387,530 B1	05-14-2002	Liu, et al.	428	559	06-14-2000
✓		A15	6,373,243 B1	04-16-2002	Takano, et al.	324	212	10-12-2000
Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
		B1					<input type="checkbox"/>	<input type="checkbox"/>
		B2					<input type="checkbox"/>	<input type="checkbox"/>
OTHER ART								
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.						
LDW	C1	ECE Signals and Systems Fall, 2002, UMD, "Experiment 2: The Controls in the Spectrum Analyzer," 8 pages						
LDW	C2	"Spectrum Analyzer Updates," June 10, 2000, 15 pages						
LDW	C3	J. Mulder, "An RMS-DC Converter Based on the Dynamic Translinear Principle," IEEE Journal of Solid-State Circuits, Vol. 32, No. 7, July 1997, Pages 1146-1150						
Examiner 7/13/05					Date Considered 7/13/05			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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U.S. Patent Documents

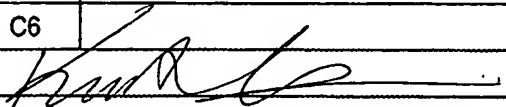
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
✓	LSW	A16	6,359,747 B1	03-19-2002	Kuo, D.S.	360	75	08-07-1998
		A17	6,587,293 B1	07-01-2003	Ding, et al.	360	51	02-29-2000
✓		A18	6,580,572 B1	06-17-2003	Yao, et al.	360	25	12-14-2000
		A19	6,574,068 B1	06-03-2003	Hampshire, et al.	360	77.08	04-18-2000
✓		A20	6,304,407 B1	10-16-2001	Baker, et al.	360	75	10-27-1998
✓		A21	6,181,492 B1	01-30-2001	Bonyhard, P.I.	360	17	03-09-1998
✓		A22	6,142,006	11-07-2000	Marchon, et al.	73	1.81	07-24-1998
✓		A23	6,097,561	08-01-2000	Wakefield, et al.	360	51	03-09-1998
✓		A24	5,996,045	11-30-1999	Lee, et al.	711	112	07-08-1997
✓		A25	5,963,029	10-05-1999	Pressesky, J.L.	324	212	01-30-1997
✓		A26	5,991,104	11-23-1999	Bonyhard, P.I.	360	15	11-27-1996
		A27	5,898,499	04-27-1999	Pressesky, J.L.	356	357	01-30-1997
✓	✓	A28	2003/0035235 A1		Ikeda, et al.	360	59	08-07-2002

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
		B3					<input type="checkbox"/>	<input type="checkbox"/>
		B4					<input type="checkbox"/>	<input type="checkbox"/>
		B5					<input type="checkbox"/>	<input type="checkbox"/>
		B6					<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
LSW	C4	"RF Up/Down Conversion Is Simplified By Linear Arrays", Intersil™, Application Note 9744, July 1997, 4 pages
LSW	C5	http://whatis.techtarget.com/definition , 2 pages
	C6	

Examiner  Date Considered 7/13/05

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